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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Active
Core Processor	ARM® Cortex®-A53
Number of Cores/Bus Width	8 Core, 64-Bit
Speed	1.6GHz
Co-Processors/DSP	-
RAM Controllers	DDR4
Graphics Acceleration	-
Display & Interface Controllers	-
Ethernet	10GbE (2), 1GbE (8)
SATA	SATA 6Gbps (1)
USB	USB 3.0 (2) + PHY
Voltage - I/O	-
Operating Temperature	-40°C ~ 105°C
Security Features	Secure Boot, TrustZone®
Package / Case	780-BFBGA, FCBGA
Supplier Device Package	780-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/l1088axe7q1a

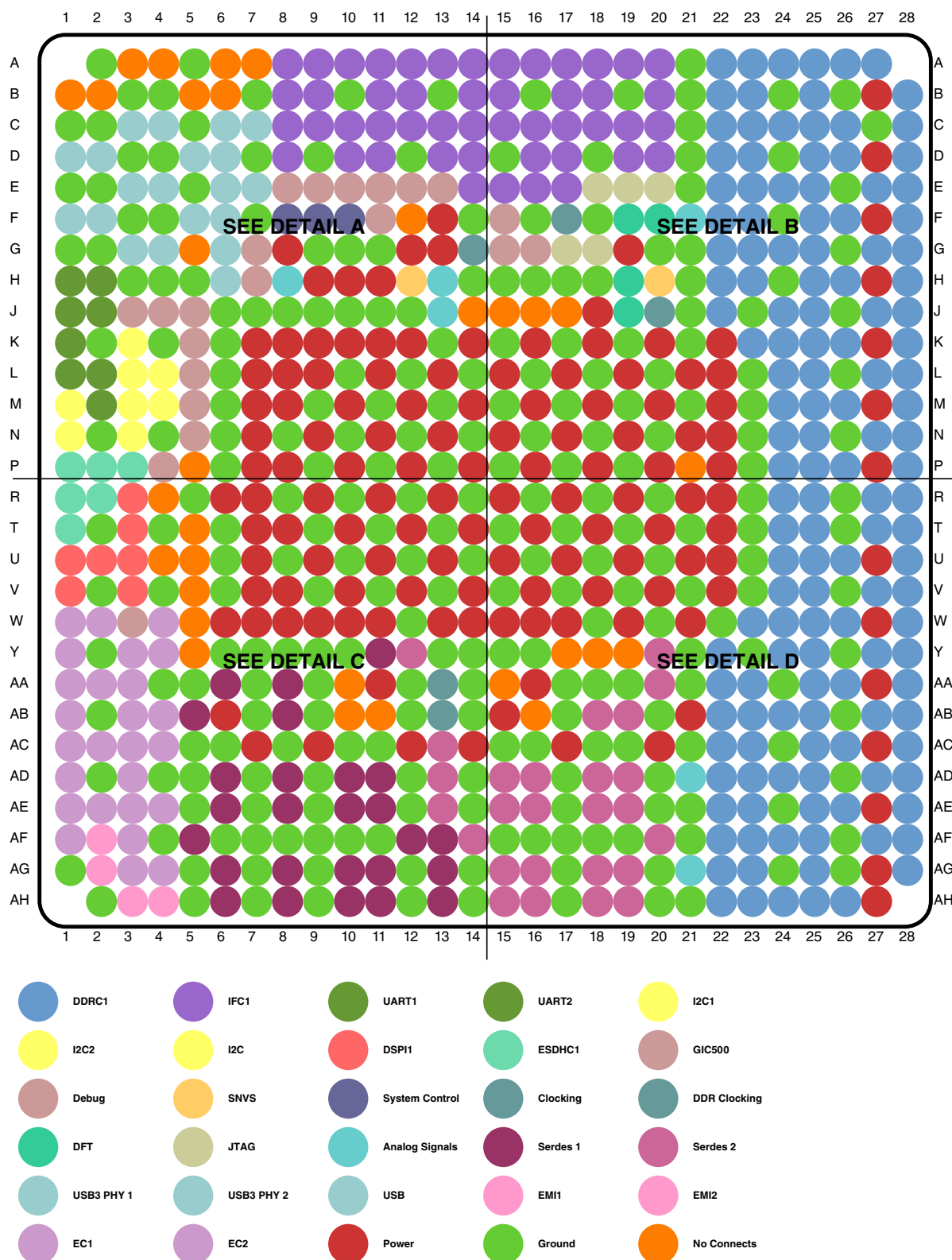


Figure 2. Complete BGA Map for the LS1088A

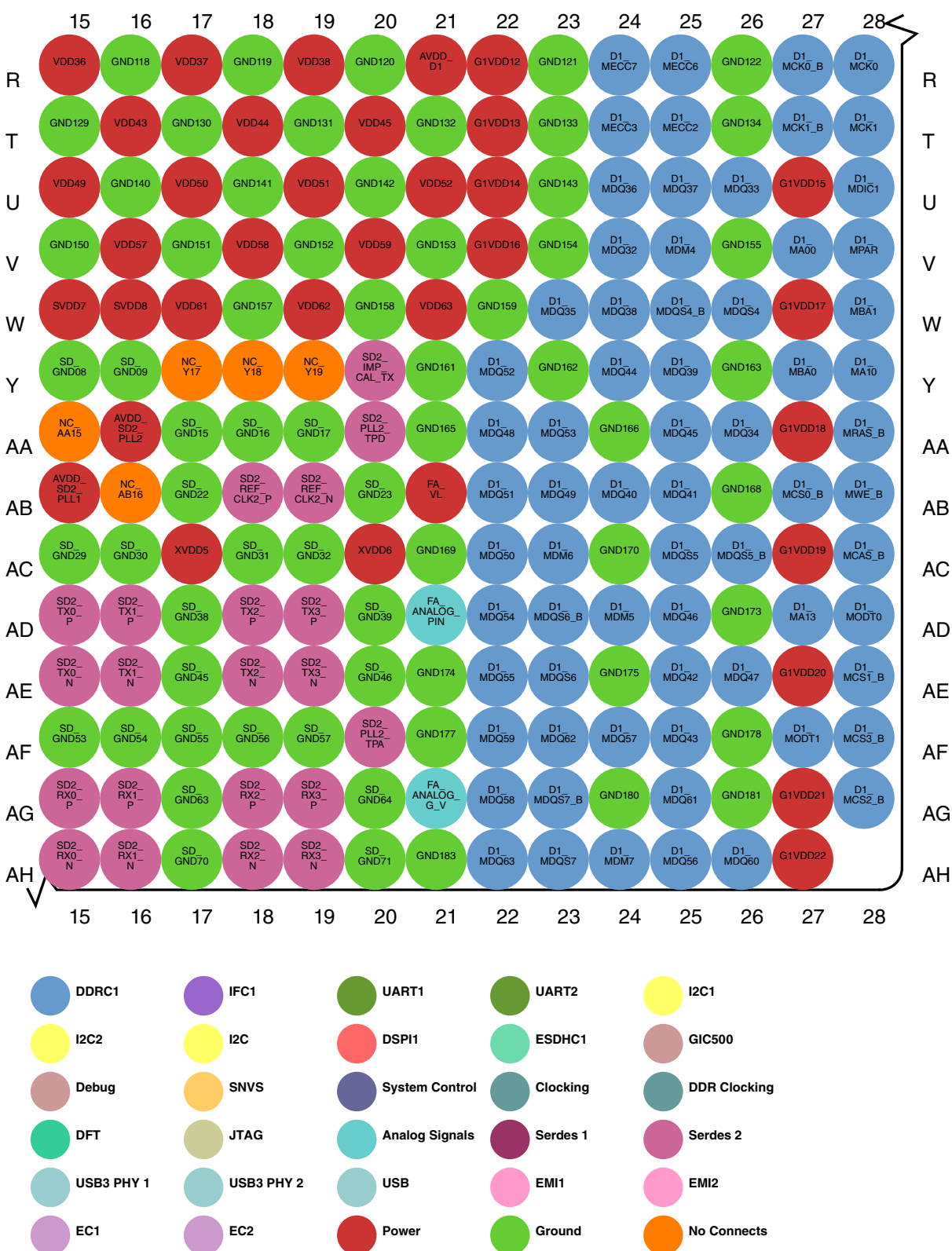


Figure 6. Detail D

Table 1. Pinout list by bus (continued)

Signal	Signal description	Package pin number	Pin type	Power supply	Notes
D1_MCS3_B	Chip Select	AF28	O	G1V _{DD}	1
D1_MDIC0	Driver Impedence Calibration	P28	IO	G1V _{DD}	3
D1_MDIC1	Driver Impedence Calibration	U28	IO	G1V _{DD}	3
D1_MDM0	Data Mask	B23	O	G1V _{DD}	---
D1_MDM1	Data Mask	H22	O	G1V _{DD}	---
D1_MDM2	Data Mask	E25	O	G1V _{DD}	---
D1_MDM3	Data Mask	J25	O	G1V _{DD}	---
D1_MDM4	Data Mask	V25	O	G1V _{DD}	---
D1_MDM5	Data Mask	AD24	O	G1V _{DD}	---
D1_MDM6	Data Mask	AC23	O	G1V _{DD}	---
D1_MDM7	Data Mask	AH24	O	G1V _{DD}	---
D1_MDM8	Data Mask	P24	O	G1V _{DD}	---
D1_MDQ00	Data	C22	IO	G1V _{DD}	---
D1_MDQ01	Data	A23	IO	G1V _{DD}	---
D1_MDQ02	Data	C26	IO	G1V _{DD}	---
D1_MDQ03	Data	A27	IO	G1V _{DD}	---
D1_MDQ04	Data	B22	IO	G1V _{DD}	---
D1_MDQ05	Data	A22	IO	G1V _{DD}	---
D1_MDQ06	Data	B25	IO	G1V _{DD}	---
D1_MDQ07	Data	A26	IO	G1V _{DD}	---
D1_MDQ08	Data	E22	IO	G1V _{DD}	---
D1_MDQ09	Data	D22	IO	G1V _{DD}	---
D1_MDQ10	Data	F23	IO	G1V _{DD}	---
D1_MDQ11	Data	G23	IO	G1V _{DD}	---
D1_MDQ12	Data	G22	IO	G1V _{DD}	---
D1_MDQ13	Data	F22	IO	G1V _{DD}	---
D1_MDQ14	Data	C24	IO	G1V _{DD}	---
D1_MDQ15	Data	E23	IO	G1V _{DD}	---
D1_MDQ16	Data	D26	IO	G1V _{DD}	---
D1_MDQ17	Data	E24	IO	G1V _{DD}	---
D1_MDQ18	Data	G24	IO	G1V _{DD}	---
D1_MDQ19	Data	H25	IO	G1V _{DD}	---
D1_MDQ20	Data	C25	IO	G1V _{DD}	---
D1_MDQ21	Data	D25	IO	G1V _{DD}	---
D1_MDQ22	Data	G25	IO	G1V _{DD}	---
D1_MDQ23	Data	H26	IO	G1V _{DD}	---
D1_MDQ24	Data	K23	IO	G1V _{DD}	---
D1_MDQ25	Data	J24	IO	G1V _{DD}	---

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Table 1. Pinout list by bus (continued)

Signal	Signal description	Package pin number	Pin type	Power supply	Notes
DIFF_SYSCLK_B	Single Source System Clock Differential (negative)	AB13	I	SV _{DD}	20
RTC/GPIO3_30	Real Time Clock	F17	I	OV _{DD}	1
SYSCLK	System Clock	G14	I	OV _{DD}	---
DDR Clocking					
DDRCLK	DDR Controller Clock	J20	I	OV _{DD}	---
DFT					
JTAG_BSR_VSEL	Reserved	J19	I	OV _{DD}	15
SCAN_MODE_B	Reserved	H19	I	OV _{DD}	10
TBSCAN_EN_B	Test Boundary Scan Enable	F19	I	OV _{DD}	6
TEST_SEL_B	Reserved	F20	I	OV _{DD}	10
JTAG					
TCK	Test Clock	E18	I	OV _{DD}	---
TDI	Test Data In	G17	I	OV _{DD}	9
TDO	Test Data Out	E20	O	OV _{DD}	2
TMS	Test Mode Select	G18	I	OV _{DD}	9
TRST_B	Test Reset	E19	I	OV _{DD}	9
Analog Signals					
D1_TPA	Reserved	F21	IO		12
FA_ANALOG_G_V	Reserved	AG21	IO		15
FA_ANALOG_PIN	Reserved	AD21	IO		15
TD1_ANODE	Thermal diode anode	J13	IO		17
TD1_CATHODE	Thermal diode cathode	H13	IO		17
TH_TPA	Reserved	H8	-	-	12
SerDes 1					
SD1_IMP_CAL_RX	SerDes Receive Impedance Calibration	Y11	I	SV _{DD}	11
SD1_IMP_CAL_TX	SerDes Transmit Impedance Calibration	AA6	I	XV _{DD}	16
SD1_PLL1_TPA	SerDes PLL 1 Test Point Analog	AF12	O	AVDD_SD1_PLL1	12
SD1_PLL1_TPD	SerDes Test Point Digital	AF13	O	XV _{DD}	12
SD1_PLL2_TPA	SerDes PLL 2 Test Point Analog	AF5	O	AVDD_SD1_PLL2	12
SD1_PLL2_TPD	SerDes Test Point Digital	AB5	O	XV _{DD}	12
SD1_REF_CLK1_N	SerDes PLL 1 Reference Clock Complement	AH13	I	SV _{DD}	---
SD1_REF_CLK1_P	SerDes PLL 1 Reference Clock	AG13	I	SV _{DD}	---
SD1_REF_CLK2_N	SerDes PLL 2 Reference Clock Complement	AB8	I	SV _{DD}	---

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Table 1. Pinout list by bus (continued)

Signal	Signal description	Package pin number	Pin type	Power supply	Notes
EC1_RXD2/GPIO2_30	Receive Data	Y1	I	LV _{DD}	1
EC1_RXD3/GPIO2_29	Receive Data	W2	I	LV _{DD}	1
EC1_RX_CLK/GPIO4_13	Receive Clock	W1	I	LV _{DD}	1
EC1_RX_DV/GPIO4_14	Receive Data Valid	AB1	I	LV _{DD}	1
EC1_TXD0/GPIO2_25	Transmit Data	AB3	O	LV _{DD}	1
EC1_TXD1/GPIO2_24	Transmit Data	AA3	O	LV _{DD}	1
EC1_TXD2/GPIO2_23	Transmit Data	Y4	O	LV _{DD}	1
EC1_TXD3/GPIO2_22	Transmit Data	Y3	O	LV _{DD}	1
EC1_TX_EN/GPIO2_26	Transmit Enable	AB4	O	LV _{DD}	1, 14
Ethernet Controller 2					
EC2_GTX_CLK/GPIO4_20	Transmit Clock Out	AC4	O	LV _{DD}	1
EC2_GTX_CLK125/GPIO4_21	Reference Clock	AG4	I	LV _{DD}	1
EC2_RXD0/GPIO4_25/ TSEC_1588_TRIG_IN2	Receive Data	AE2	I	LV _{DD}	1
EC2_RXD1/GPIO4_24/ TSEC_1588_PULSE_OUT1	Receive Data	AE1	I	LV _{DD}	1
EC2_RXD2/GPIO4_23	Receive Data	AD1	I	LV _{DD}	1
EC2_RXD3/GPIO4_22	Receive Data	AC2	I	LV _{DD}	1
EC2_RX_CLK/GPIO4_26/ TSEC_1588_CLK_IN	Receive Clock	AC1	I	LV _{DD}	1
EC2_RX_DV/GPIO4_27/ TSEC_1588_TRIG_IN1	Receive Data Valid	AF1	I	LV _{DD}	1
EC2_TXD0/GPIO4_18/ TSEC_1588_PULSE_OUT2	Transmit Data	AF3	O	LV _{DD}	1
EC2_TXD1/GPIO4_17/ TSEC_1588_CLK_OUT	Transmit Data	AE4	O	LV _{DD}	1
EC2_TXD2/GPIO4_16/ TSEC_1588_ALARM_OUT1	Transmit Data	AE3	O	LV _{DD}	1
EC2_TXD3/GPIO4_15/ TSEC_1588_ALARM_OUT2	Transmit Data	AD3	O	LV _{DD}	1
EC2_TX_EN/GPIO4_19	Transmit Enable	AG3	O	LV _{DD}	1, 14
General Purpose Input/Output					
GPIO1_00/IFC_AD00/ cfg_gpinput0	General Purpose Input/Output	B12	O	OV _{DD}	1, 4
GPIO1_01/IFC_AD01/ cfg_gpinput1	General Purpose Input/Output	A11	O	OV _{DD}	1, 4
GPIO1_02/IFC_AD02/ cfg_gpinput2	General Purpose Input/Output	B11	O	OV _{DD}	1, 4
GPIO1_03/IFC_AD03/ cfg_gpinput3	General Purpose Input/Output	A10	O	OV _{DD}	1, 4
GPIO1_04/IFC_AD04/ cfg_gpinput4	General Purpose Input/Output	A9	O	OV _{DD}	1, 4

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Table 1. Pinout list by bus (continued)

Signal	Signal description	Package pin number	Pin type	Power supply	Notes
GND141	Core, Platform and PLL Ground	U18	---	---	---
GND142	Core, Platform and PLL Ground	U20	---	---	---
GND143	Core, Platform and PLL Ground	U23	---	---	---
GND144	Core, Platform and PLL Ground	V2	---	---	---
GND145	Core, Platform and PLL Ground	V4	---	---	---
GND146	Core, Platform and PLL Ground	V6	---	---	---
GND147	Core, Platform and PLL Ground	V9	---	---	---
GND148	Core, Platform and PLL Ground	V11	---	---	---
GND149	Core, Platform and PLL Ground	V13	---	---	---
GND150	Core, Platform and PLL Ground	V15	---	---	---
GND151	Core, Platform and PLL Ground	V17	---	---	---
GND152	Core, Platform and PLL Ground	V19	---	---	---
GND153	Core, Platform and PLL Ground	V21	---	---	---
GND154	Core, Platform and PLL Ground	V23	---	---	---
GND155	Core, Platform and PLL Ground	V26	---	---	---
GND156	Core, Platform and PLL Ground	W12	---	---	---
GND157	Core, Platform and PLL Ground	W18	---	---	---
GND158	Core, Platform and PLL Ground	W20	---	---	---
GND159	Core, Platform and PLL Ground	W22	---	---	---
GND160	Core, Platform and PLL Ground	Y2	---	---	---
GND161	Core, Platform and PLL Ground	Y21	---	---	---
GND162	Core, Platform and PLL Ground	Y23	---	---	---

Table continues on the next page...

Table 1. Pinout list by bus (continued)

Signal	Signal description	Package pin number	Pin type	Power supply	Notes
SD_GND46	SerDes core logic, transceiver, and PLL ground	AE20	---	---	18
SD_GND47	SerDes core logic, transceiver, and PLL ground	AF6	---	---	18
SD_GND48	SerDes core logic, transceiver, and PLL ground	AF7	---	---	18
SD_GND49	SerDes core logic, transceiver, and PLL ground	AF8	---	---	18
SD_GND50	SerDes core logic, transceiver, and PLL ground	AF9	---	---	18
SD_GND51	SerDes core logic, transceiver, and PLL ground	AF10	---	---	18
SD_GND52	SerDes core logic, transceiver, and PLL ground	AF11	---	---	18
SD_GND53	SerDes core logic, transceiver, and PLL ground	AF15	---	---	18
SD_GND54	SerDes core logic, transceiver, and PLL ground	AF16	---	---	18
SD_GND55	SerDes core logic, transceiver, and PLL ground	AF17	---	---	18
SD_GND56	SerDes core logic, transceiver, and PLL ground	AF18	---	---	18
SD_GND57	SerDes core logic, transceiver, and PLL ground	AF19	---	---	18
SD_GND58	SerDes core logic, transceiver, and PLL ground	AG5	---	---	18
SD_GND59	SerDes core logic, transceiver, and PLL ground	AG7	---	---	18
SD_GND60	SerDes core logic, transceiver, and PLL ground	AG9	---	---	18
SD_GND61	SerDes core logic, transceiver, and PLL ground	AG12	---	---	18
SD_GND62	SerDes core logic, transceiver, and PLL ground	AG14	---	---	18
SD_GND63	SerDes core logic, transceiver, and PLL ground	AG17	---	---	18
SD_GND64	SerDes core logic, transceiver, and PLL ground	AG20	---	---	18
SD_GND65	SerDes core logic, transceiver, and PLL ground	AH5	---	---	18
SD_GND66	SerDes core logic, transceiver, and PLL ground	AH7	---	---	18
SD_GND67	SerDes core logic, transceiver, and PLL ground	AH9	---	---	18

Table continues on the next page...

adjust the memory clocks by $\frac{1}{2}$ applied cycle for data rates of 1866 MT/s or less and $\frac{9}{16}$ applied cycle for data rates greater than 1866 MT/s. It is recommended that, during system validation, memory clocks are adjusted to best fit the particular system design.

This figure shows the DDR4 SDRAM interface output timing for the MCK to MDQS skew measurement (t_{DDKMH}).

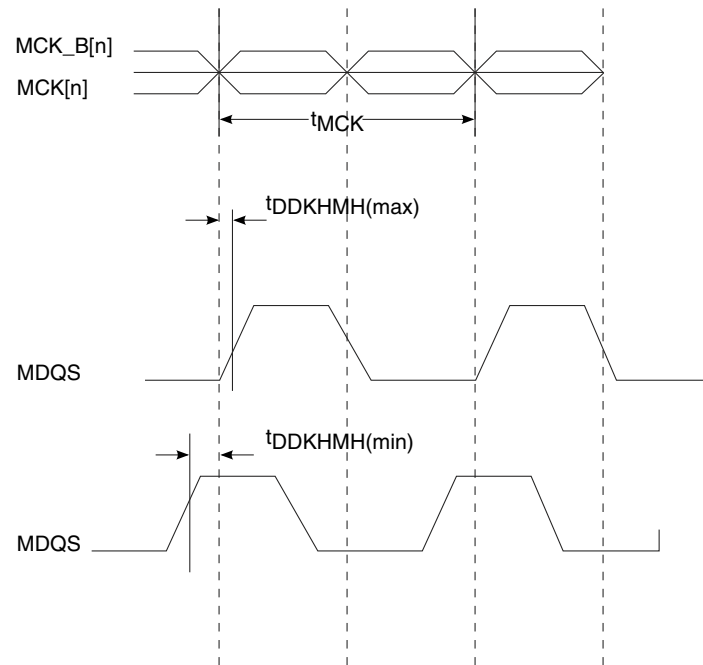


Figure 12. t_{DDKMH} timing diagram

This figure shows the DDR4 SDRAM output timing diagram.

3.12 Enhanced secure digital host controller (eSDHC)

This section describes the DC and AC electrical specifications for the eSDHC interface.

3.12.1 eSDHC DC electrical characteristics

This table provides the DC electrical characteristics for the eSDHC interface.

Table 33. eSDHC interface DC electrical characteristics (E/DV_{DD}=3.3 V)³

Characteristic	Symbol	Min	Max	Unit	Notes
Input high voltage	V _{IH}	0.7 x E/DV _{DD}	-	V	1
Input low voltage	V _{IL}	-	0.25 x E/DV _{DD}	V	1
Output high voltage (I _{OH} = -100 µA at E/DV _{DD} min)	V _{OH}	0.75 x E/DV _{DD}	-	V	-
Output low voltage (I _{OL} = 100 µA at E/DV _{DD} min)	V _{OL}	-	0.125 x E/DV _{DD}	V	-
Output high voltage (I _{OH} = -100 µA)	V _{OH}	E/DV _{DD} - 0.2	-	V	2
Output low voltage (I _{OL} = 2 mA)	V _{OL}	-	0.3	V	2
Input/output leakage current (I _{IN} /I _{OZ})	(I _{IN} /I _{OZ})	-10	10	µA	2
Notes: 1. The min V _{IL} and max V _{IH} values are based on the respective min and max EV _{IN} values found in the Table 3 . 2. Open-drain mode is for MMC cards only. 3. At recommended operating conditions with E/DV _{DD} = 3.3 V.					

Table 34. eSDHC interface DC electrical characteristics (E/D/OV_{DD}=1.8 V)³

Characteristic	Symbol	Min	Max	Unit	Notes
Input high voltage	V _{IH}	0.7 x E/D/OV _{DD}	-	V	1
Input low voltage	V _{IL}	-	0.3 x E/D/OV _{DD}	V	1
Output high voltage (I _{OH} = -2 mA at E/D/OV _{DD} min)	V _{OH}	E/D/OV _{DD} - 0.45	-	V	-
Output low voltage (I _{OL} = 2 mA at EV _{DD} min)	V _{OL}	-	0.45	V	-
Output high voltage (I _{OH} = -100 µA)	V _{OH}	E/D/OV _{DD} - 0.2	-	V	2
Output low voltage (I _{OL} = 2 mA)	V _{OL}	-	0.3	V	2

Table continues on the next page...

3.14.1 GPIO DC electrical characteristics

This table provides the DC electrical characteristics for the GPIO interface operating at $D/EV_{DD} = 3.3\text{ V}$.

Table 52. GPIO DC electrical characteristics ($D/EV_{DD} = 3.3\text{ V}$)¹

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage	V_{IH}	$0.7 \times D/EV_{DD}$	-	V	2
Input low voltage	V_{IL}	-	$0.2 \times D/EV_{DD}$	V	2
Input current ($V_{IN} = 0\text{V}$ or $V_{IN} = LV_{DD}$)	I_{IN}	-	± 50	μA	3
Output high voltage ($D/EV_{DD} = \text{min}$, $I_{OH} = -2\text{ mA}$)	V_{OH}	2.4	-	V	-
Output low voltage ($D/EV_{DD} = \text{min}$, $I_{OL} = 2\text{ mA}$)	V_{OL}	-	0.4	V	-
1. For recommended operating conditions, see Table 3 . 2. The min V_{IL} and max V_{IH} values are based on the respective min and max DV_{IN}/EV_{IN} values found in Table 3 . 3. The symbol DV_{IN}/EV_{IN} represents the input voltage of the supply referenced in Table 3 .					

This table provides the DC electrical characteristics for the GPIO interface operating at $TV_{DD} = 2.5\text{ V}$.

Table 53. GPIO DC electrical characteristics ($TV_{DD} = 2.5\text{ V}$)¹

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage	V_{IH}	$0.7 \times TV_{DD}$	-	V	2
Input low voltage	V_{IL}	-	$0.2 \times TV_{DD}$	V	2
Input current ($V_{IN} = 0\text{V}$ or $V_{IN} = LV_{DD}$)	I_{IN}	-	± 50	μA	3
Output high voltage ($TV_{DD} = \text{min}$, $I_{OH} = -1\text{ mA}$)	V_{OH}	2.0	-	V	-
Output low voltage ($TV_{DD} = \text{min}$, $I_{OL} = 1\text{ mA}$)	V_{OL}	-	0.4	V	-
1. For recommended operating conditions, see Table 3 . 2. The min V_{IL} and max V_{IH} values are based on the respective min and max TV_{IN} values found in Table 3 . 3. The symbol TV_{IN} represents the input voltage of the supply referenced in Table 3 .					

This table provides the DC electrical characteristics for the GPIO interface operating at $D/E/TV_{DD} = 1.8\text{ V}$.

Table 54. GPIO DC electrical characteristics ($D/E/TV_{DD} = 1.8\text{ V}$)¹

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage	V_{IH}	$0.7 \times D/E/TV_{DD}$	-	V	2

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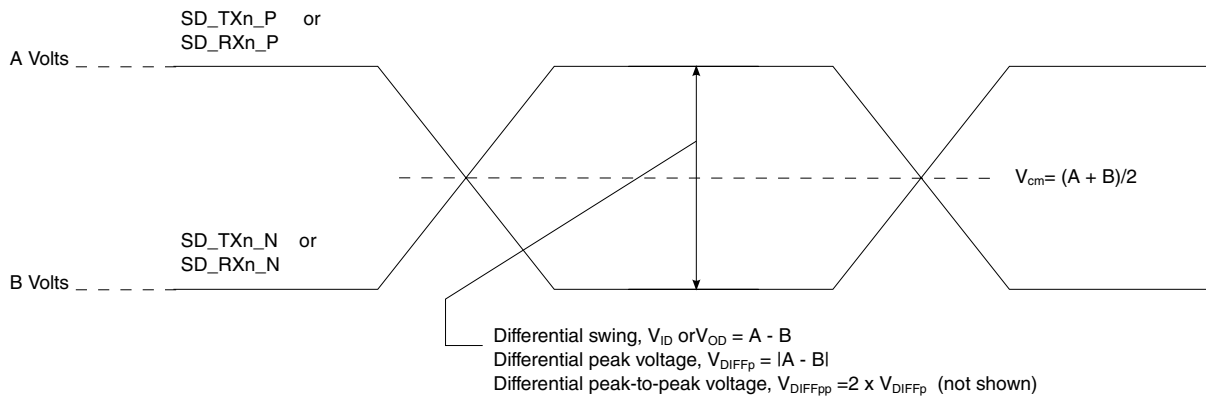


Figure 29. Differential voltage definitions for transmitter or receiver

Using this waveform, the definitions are as described in the following list. To simplify the illustration, the definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment:

Single-Ended Swing

The transmitter output signals and the receiver input signals SD_TXn_P, SD_TXn_N, SD_RXn_P and SD_RXn_N each have a peak-to-peak swing of $A - B$ volts. This is also referred to as each signal wire's single-ended swing.

Differential Output Voltage, V_{OD} (or Differential Output Swing)

The differential output voltage (or swing) of the transmitter, V_{OD} , is defined as the difference of the two complementary output voltages: $V_{SD_TXn_P} - V_{SD_TXn_N}$. The V_{OD} value can be either positive or negative.

Differential Input Voltage, V_{ID} (or Differential Input Swing)

The differential input voltage (or swing) of the receiver, V_{ID} , is defined as the difference of the two complementary input voltages: $V_{SD_RXn_P} - V_{SD_RXn_N}$. The V_{ID} value can be either positive or negative.

Differential Peak Voltage, V_{DIFFp}

The peak value of the differential transmitter output signal or the differential receiver input signal is defined as the differential peak voltage, $V_{DIFFp} = |A - B|$ volts.

Differential Peak-to-Peak, $V_{DIFFp-p}$

Because the differential output signal of the transmitter and the differential input signal of the receiver each range from $A - B$ to $-(A - B)$ volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as differential peak-to-peak voltage, $V_{DIFFp-p} = 2 \times V_{DIFFp} = 2 \times |A - B|$ volts, which is twice the differential swing in amplitude, or twice the differential peak. For example, the output differential peak-to-peak voltage can also be calculated as $V_{TX-DIFFp-p} = 2 \times |V_{OD}|$.

Differential Waveform

The differential waveform is constructed by subtracting the inverting signal (SD_TXn_N, for example) from the non-inverting signal (SD_TXn_P, for example)

Table 69. PCI Express 3.0 (8 GT/s) differential transmitter output DC characteristics ($XV_{DD} = 1.35\text{ V}$)³

Parameter	Symbol	Min	Typical	Max	Units	Notes
Full swing transmitter voltage with no TX Eq	$V_{TX-FS-NO-EQ}$	800	—	1300	mVp-p	See Note 1.
Reduced swing transmitter voltage with no TX Eq	$V_{TX-RS-NO-EQ}$	400	—	1300	mV	See Note 1.
De-emphasized differential output voltage (ratio)	$V_{TX-DE-RATIO-3.5dB}$	3.0	3.5	4.0	dB	—
De-emphasized differential output voltage (ratio)	$V_{TX-DE-RATIO-6.0dB}$	5.5	6.0	6.5	dB	—
Minimum swing during EIEOS for full swing	$V_{TX-EIEOS-FS}$	250	—	—	mVp-p	See Note 2
Minimum swing during EIEOS for reduced swing	$V_{TX-EIEOS-RS}$	232	—	—	mVp-p	See Note 2
DC differential transmitter impedance	$Z_{TX-DIFF-DC}$	80	100	120	Ω	Transmitter DC differential mode low impedance
Transmitter DC Impedance	Z_{TX-DC}	40	50	60	Ω	Required transmitter D+ as well as D- DC impedance during all states

Notes:

1. Voltage measurements for $V_{TX-FS-NO-EQ}$ and $V_{TX-RS-NO-EQ}$ are made using the 64-zeroes/64-ones pattern in the compliance pattern.
2. Voltage limits comprehend both full swing and reduced swing modes. The transmitter must reject any changes that would violate this specification. The maximum level is covered in the $V_{TX-FS-NO-EQ}$ measurement which represents the maximum peak voltage the transmitter can drive. The $V_{TX-EIEOS-FS}$ and $V_{TX-EIEOS-RS}$ voltage limits are imposed to guarantee the EIEOS threshold of 175 mV_{P-P} at the receiver pin. This parameter is measured using the actual EIEOS pattern that is part of the compliance pattern and then removing the ISI contribution of the breakout channel.
3. For recommended operating conditions, see [Table 3](#).

3.16.4.3.2 PCI Express DC physical layer receiver specifications

This section discusses the PCI Express DC physical layer receiver specifications for 2.5 GT/s, 5 GT/s, and 8 GT/s.

This table defines the DC specifications for the PCI Express 2.0 (2.5 GT/s) differential input at all receivers. The parameters are specified at the component pins.

Table 70. PCI Express 2.0 (2.5 GT/s) differential receiver input DC specifications ($SV_{DD} = 0.9V/1.0\text{ V}$)⁴

Parameter	Symbol	Min	Typ	Max	Units	Notes
Differential input peak-to-peak voltage	$V_{RX-DIFFp-p}$	175	1000	1200	mV	$V_{RX-DIFFp-p} = 2 \times V_{RX-D+} - V_{RX-D-} $ See Note 1.

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3.16.8.3 XFI AC timing specifications

NOTE

The AC specifications do not include RefClk jitter.

This table defines the XFI transmitter AC timing specifications.

Table 104. XFI transmitter AC timing specifications

Parameter	Symbol	Min	Typ	Max	Unit
Transmitter baud Rate	T_{BAUD}	10.3125-100ppm	10.3125	10.3125+100ppm	Gb/s
Unit Interval	UI	-	96.96	-	ps
Deterministic jitter	D_J	-	-	0.15	UI p-p
Total jitter tolerance	T_J	-	-	0.3	UI p-p

This table defines the XFI receiver AC timing specifications. RefClk jitter is not included.

Table 105. XFI receiver AC timing specifications

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Unit Interval	UI	-	96.96	-	ps	-
Receiver baud rate	R_{BAUD}	10.3125-100ppm	10.3125	10.3125+100ppm	Gb/s	-
Total non-EQJ jitter	$T_{\text{NON-EQJ}}$	-	-	0.45	UI p-p	1
Total jitter tolerance	T_J	-	-	0.65	UI p-p	1, 2
<p>1. The total jitter (T_J) consists of Random Jitter (RJ), Duty Cycle Distortion (DCD), Periodic Jitter (PJ), and Inter-Symbol Interference (ISI). Non-EQJ jitter can include duty cycle distortion (DCD), random jitter (RJ), and periodic jitter (PJ). Non-EQJ jitter is uncorrelated to the primary data stream with exception of the DCD and so cannot be equalized by the receiver under test. It can exhibit a wide spectrum. Non - EQJ = $T_J - \text{ISI} = \text{RJ} + \text{DCD} + \text{PJ}$.</p> <p>2. The XFI channel has a loss budget of 9.6 dB @5.5GHz. The channel loss including connector @ 5.5GHz is 6dB. The channel crosstalk and reflection margin is 3.6dB. Manual tuning of TX Equalization and amplitude will be required for performance optimization.</p>						

This figure shows the sinusoidal jitter tolerance of XFI receiver.

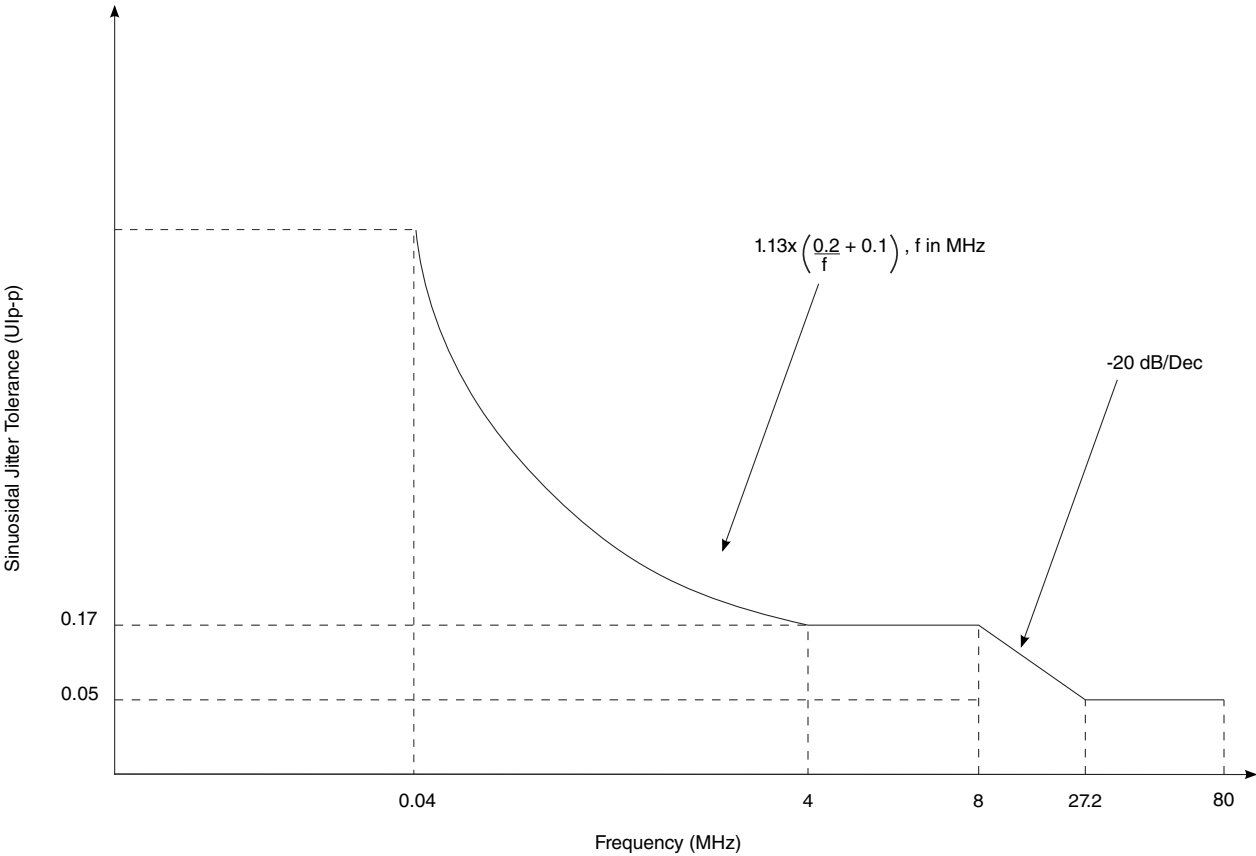


Figure 44. XFI host receiver input sinusoidal jitter tolerance

3.16.9 1000Base-KX interface

This section describes the electrical characteristics for the 1000Base-KX interface. Only AC-coupled operation is supported.

3.16.9.1 1000Base-KX DC electrical characteristics

This table describes the 1000Base-KX SerDes transmitter DC electrical characteristics at TP1 per IEEE Std 802.3ap-2007. Transmitter DC electrical characteristics are measured at the transmitter outputs (SDn_TXn_P and SDn_TXn_N).

Table 106. 1000Base-KX transmitter DC electrical characteristics¹

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Output differential voltage	V _{TX-DIFFp-p}	800.0	-	1600.0	mV	2

Table continues on the next page...

Table 125. Integrated flash controller IFC-NAND NVDDR interface AC timing specifications (OVDD = 1.8 V) (continued)

Parameter	Symbol	I/O	Min	Max	Unit	Notes
Command, Address, Data delay (command to command, address to address, command to address, address to command, command/ address to start of data) Fast	tCADf	O	TCAD - 150 (ps)	TCAD + 150 (ps)	t _{IP_CLK}	Figure 68
Command, Address, Data delay (command to command, address to address, command to address, address to command, command/ address to start of data) slow	tCADs	O	TCAD - 150 (ps)	TCAD + 150 (ps)	t _{IP_CLK}	Figure 68
Command/address DQ hold time	t _{CAH}	O	2 + 150 (ps)	-	ns	Figure 68
CLE and ALE hold time	t _{CALH}	O	2 + 150 (ps)	-	ns	Figure 68
CLE and ALE setup time	t _{CALS}	O	2 + 150 (ps)	-	ns	Figure 68
Command/address DQ setup time	t _{CAS}	O	2 + 150 (ps)	-	ns	Figure 68
CE# hold time	t _{CH}	O	2 + 150 (ps)	-	ns	Figure 68
Average clock cycle time, also known as tCK	t _{CK} (avg) or t _{CK}	O	10	-	ns	Figure 68
Absolute clock period, measured from rising edge to the next consecutive rising edge	t _{CK} (abs)	O	t _{CK} (avg) + t _{JIT} (per) min	t _{CK} (avg) + t _{JIT} (per) max	ns	Figure 68
Clock cycle high	t _{CKH} (abs)	O	0.45	0.55	tCK	Figure 68
Clock cycle low	t _{CKL} (abs)	O	0.45	0.55	tCK	Figure 68
Data input end to W/R# high B16	t _{CKWR}	O	TCKWR - 150 (ps)	TCKWR + 150 (ps)	t _{IP_CLK}	Figure 71
CE# setup time	t _{CS}	O	TCS - 150 (ps)	TCS + 150 (ps)	t _{IP_CLK}	Figure 70
Data DQ hold time	t _{DH}	O	1050	-	ps	Figure 70
Access window of DQS from CLK	t _{DQSCK}	I	-	20 + 150 (ps)	ns	Figure 71
W/R# low to DQS/DQ driven by device	t _{DQSD}	I	-150 (ps)	18 + 150 (ps)	ns	Figure 71
DQS output high pulse width	t _{DQSH}	O	0.45	0.55	tCK	Figure 70
W/R# high to DQS/DQ tri-state by device	t _{DQSHZ}	O	RHZ - 150 (ps)	RHZ + 150 (ps)	t _{IP_CLK}	Figure 68
DQS output low pulse width	t _{DQSL}	O	0.45	0.55	tCK	Figure 70

Table continues on the next page...

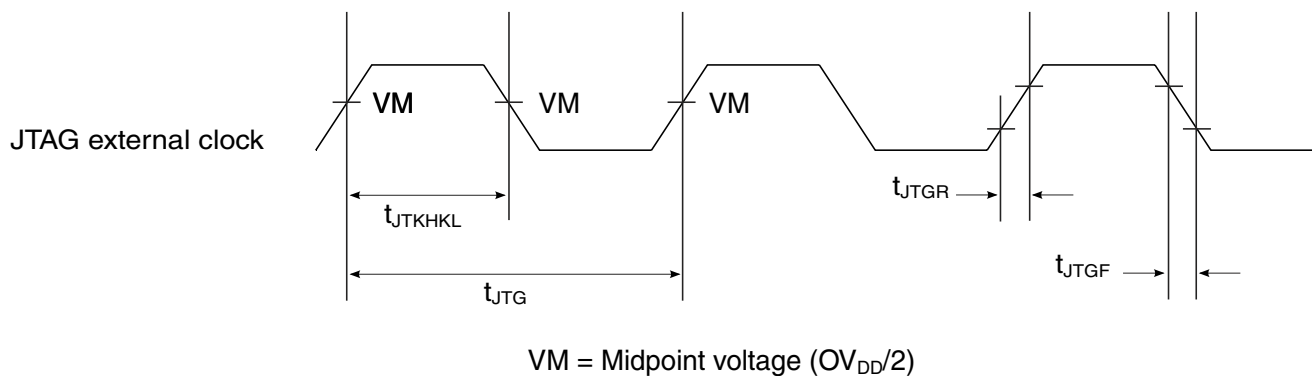


Figure 79. JTAG clock input timing diagram

This figure shows the TRST_B timing diagram.

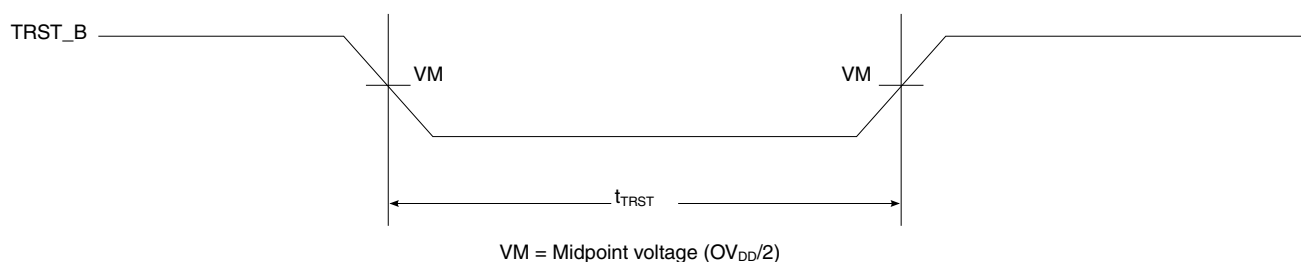


Figure 80. TRST_B timing diagram

This figure shows the boundary-scan timing diagram.

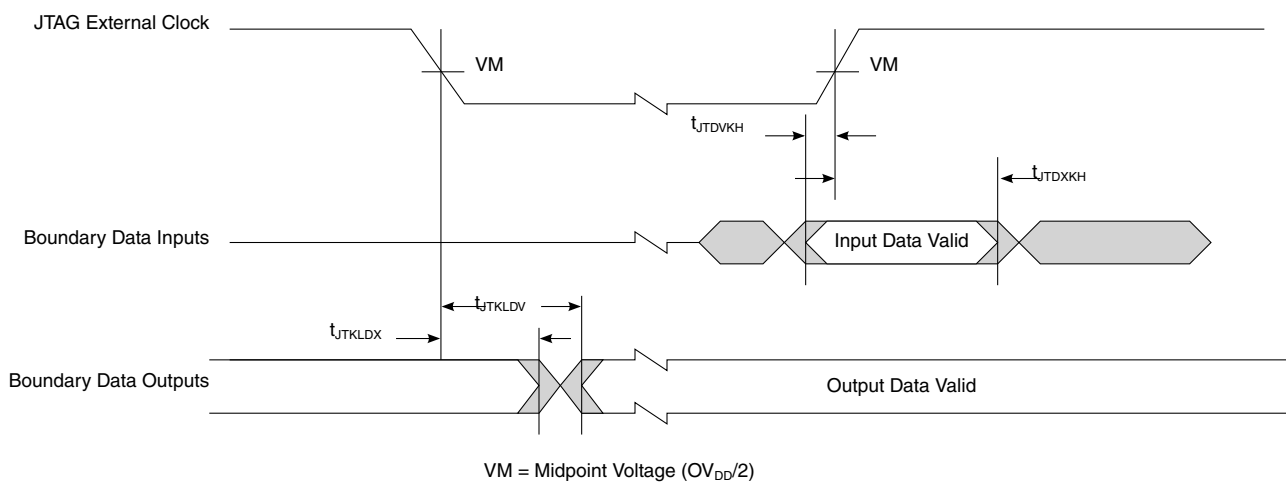


Figure 81. Boundary-scan timing diagram

3.20 Quad serial peripheral interface (QuadSPI)

This section describes the DC and AC electrical characteristics for the QuadSPI interface.

3.20.1 QuadSPI DC electrical characteristics

This table provides the DC electrical characteristics for the QuadSPI interface operating at $OV_{DD} = 1.8V$.

Table 128. QuadSPI DC electrical characteristics¹

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage	V_{IH}	$0.7 \times OV_{DD}$	-	V	2
Input low voltage	V_{IL}	-	$0.3 \times OV_{DD}$	V	2
Input current ($0V \leq V_{IN} \leq OV_{DD}$)	I_{IN}	-	± 50	μA	3
Output high voltage ($OV_{DD} = \text{min}$, $I_{OH} = -100 \mu A$)	V_{OH}	$OV_{DD} - 0.2$	-	V	-
Output low voltage ($OV_{DD} = \text{min}$, $I_{OL} = 100 \mu A$)	V_{OL}	-	0.2	V	-
1. For recommended operating conditions, see Table 3 . 2. The min V_{IL} and max V_{IH} values are based on the respective min and max OV_{IN} values found in Table 3 . 3. Note that the symbol OV_{IN} represents the input voltage of the supply referenced in the Recommended Operating Conditions table.					

3.20.2 QuadSPI AC timing specifications

This section describes the QuadSPI timing specifications in both SDR and DDR modes. All data is based on a negative edge data launch from the device and a positive edge data capture, as shown in the timing figures in this section.

This table provides the QuadSPI input and output timing in SDR mode ($MCR[DQS_EN] = 0$, regarding to the 1st sample point. See $qSPI_SMPR[xSDLY, xSPHS]$ in the corresponding chip reference manual for different sampling points). Note that T represents the clock period, j represents $qSPI_FLSHCR[TCSH]$, and k depends on $qSPI_FLSHCR[TCSS]$.

Table 129. QuadSPI SDR mode input and output timing

Parameter	Symbol	Min	Max	Unit
Clock rise/fall time	T_{RISE}/T_{FALL}	1.0	-	ns
CS output hold time	$t_{NIKHOX2}$	$-3.3 + j * T$	-	ns
CS output delay	$t_{NIKHOV2}$	$-3.0 + k * T$	-	ns

Table continues on the next page...

Electrical characteristics

This table provides the QuadSPI input and output timing in DDR mode with external DQS/delay chain (MCR[DQS_EN] = 1, regarding to the 1st sample point). Note that T represents the clock period, j depends on the value of qSPI_FLSHCR[TCSH], k depends on qSPI_FLSHCR[TCSS], and m depends on QSPI_FLSHCR[TDH].

Table 131. QuadSPI DDR mode input and output timing

Parameter	Symbol	Min	Max	Unit
Clock rise/fall time	T_{RISE}/T_{FALL}	1.0	-	ns
CS output hold time	$t_{NIKHOX2}$	$3.3 + T * j$	-	ns
CS output delay	$t_{NIKHOV2}$	$-3.0 + k * T$	-	ns
DQS to data skew	t_{NIDSH}/t_{NIDSL}	-0.9	0.9	ns
Output data valid	t_{NIKHOV}	-	$0.9 + m * T/8$	ns
Output data hold	t_{NIKHOX}	$-0.9 + m * T/8$	-	ns

This figure shows the QuadSPI AC timing in DDR mode.

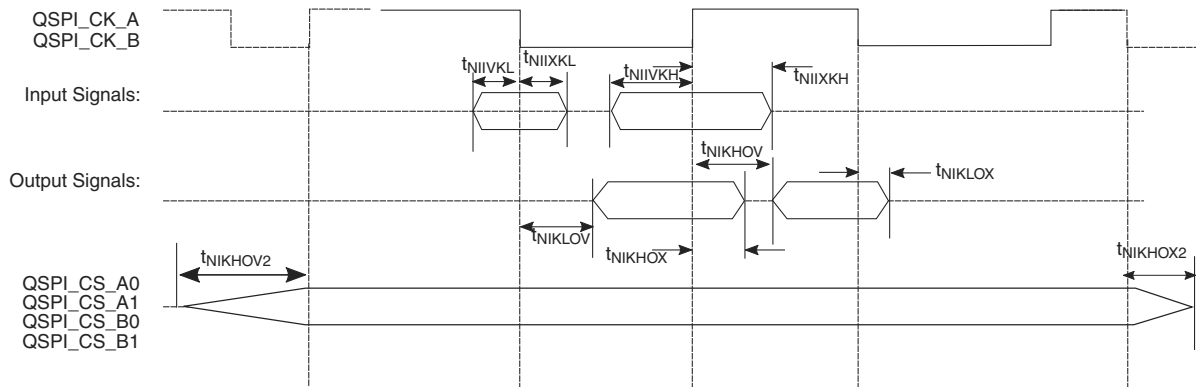


Figure 83. QuadSPI AC timing — DDR mode

This figure shows the QuadSPI data input timing in DDR mode with an external DQS.

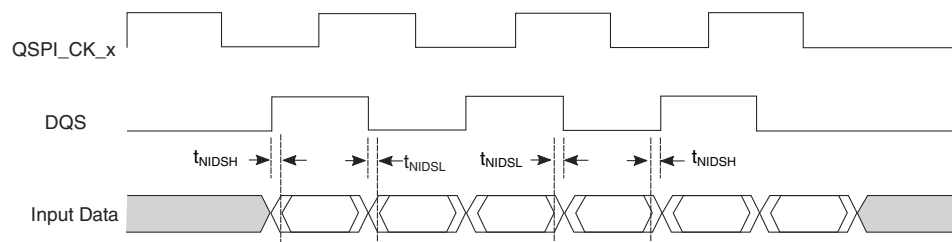


Figure 84. QuadSPI input AC timing — DDR mode with an external DQS

Table 147. Processor, platform, and memory clocking specifications

Characteristic	Maximum processor core frequency						Unit	Notes
	1200 MHz		1400 MHz		1600 MHz			
	Min	Max	Min	Max	Min	Max		
Core cluster group PLL frequency	600	1200	600	1400	600	1600	MHz	1
Platform clock frequency	400	500	400	600	400	700	MHz	1
Memory bus clock frequency	650	800	650	900	650	1050	MHz	1, 2
IFC clock frequency	-	100	-	100	-	100	MHz	3
<p>1. Caution:The coherency domain clock to SYSCLK ratio and core to SYSCLK ratio settings must be chosen such that the resulting SYSCLK frequency, core frequency, coherency domain and platform clock frequency do not exceed their respective maximum or minimum operating frequencies.</p> <p>2. The memory bus clock speed is half the DDR4 data rate.</p> <p>3. The integrated flash controller (IFC) clock speed on IFC_CLK[0:1] is determined by the platform clock divided by the IFC ratio programmed in CCR[CLKDIV]. See the chip reference manual for more information.</p>								

4.2 Power supply design

For additional details on the power supply design, see AN5144, QorIQ LS1088A Design Checklist.

4.2.1 Voltage ID (VID) controllable supply

To guarantee performance and power specifications, a specific method of selecting the optimum voltage-level must be implemented when the chip is used. As part of the chip's boot process, software must read the VID efuse values stored in the Fuse Status register (FUSESR) and then configure the external voltage regulator based on this information. This method requires a point of load voltage regulator for each chip. When VID option is used, the V_{DD} supply should be separated from the SerDes 1.0 V supply SnV_{DD} . It is required in order to control the V_{DD} supply only.

NOTE

During the power-on reset process, the fuse values are read and stored in the FUSESR. It is expected that the chip's boot code reads the FUSESR value very early in the boot sequence and updates the regulator accordingly.

The default voltage regulator setting that is safe for the system to boot is the recommended operating V_{DD} at initial start-up of 1.025 V. It is highly recommended to select a regulator with a V_{out} range of at least 0.9 V to 1.1 V, with a resolution of 12.5 mV or better, when implementing a VID solution.

5.1 Recommended thermal model

Information about Flotherm models of the package or thermal data not available in this document can be obtained from your local NXP sales office.

5.2 Temperature diode

The chip has a temperature diode on the microprocessor that can be used in conjunction with other system temperature monitoring devices (such as Analog Devices, ADT7461A). These devices feature series resistance cancellation using three current measurements, where up to 1.5 k Ω of resistance can be automatically cancelled from the temperature result, allowing noise filtering and a more accurate reading.

The following are the specifications of the chip's on-board temperature diode:

Operating range: TBD

Ideality factor TBD; Temperature range TBD

5.3 Thermal management information

This section provides thermal management information for the flip-chip, plastic-ball, grid array (FC-PBGA) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material.

The recommended attachment method to the heat sink is illustrated in [Figure 95](#). The heat sink should be attached to the printed-circuit board with the spring force centered over the die. This spring force should not exceed 15 pounds force.